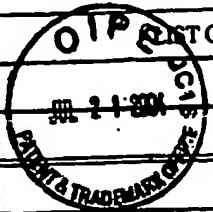
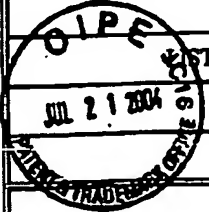


U.S. Department of Commerce, Patent and Trademark Office					Docket No.: 3816.06-C1			
					Serial No.: 10/829,641			
 LIST OF RELEVANT ART CITED BY APPLICANT (Use several sheets if necessary)					Applicant: Ranaan ZEHAVI et al.			
					Filing Date: April 22, 2004			
					Group: 2818			
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
MA	AA	5,492,229	02/2096	Tanaka et al.	211	41.18	_____	
MA	AB	5,516,283	05/14/96	Schrems	432	241	_____	
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FOREIGN PATENT DOCUMENTS (Translation)								
		Document Number	Date	Country	Class	Subclass	Yes	No
MA	AL	WO 00/21119	04/13/00	PCT	_____	_____	X	
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	AN							
	AO							
	AP							
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
	AR	anonymous, "Epi-II advanced Wafer," MEMC Applications Note, AE-003, March 2000, pp. 1-4						
	AS	anonymous, "Thin epi layers shown to improve gate oxide integrity performance," MEMC, date unknown, 1.p						
	AT							
Examiner <i>Adley</i>			Date Considered <i>9-29-04</i>					
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					Applicant: Raanan Y. ZEHAVI et al.			
					Filing Date: April 22, 2004			
					Group: 2818			
<b>U.S. PATENT DOCUMENTS</b>								
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	AG							
	AH							
<b>FOREIGN PATENT DOCUMENTS (Translation)</b>								
		Document Number	Date	Country	Class	Subclass	Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>								
	AR							
	AS							
	AT							
Examiner <i>MD</i>			Date Considered <i>9-29-04</i>					
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